

Notice of References Cited	Application/Control No. 09/845,006	Applicant(s)/Patent Under Reexamination SCHINDLER, HANSGEORG	
	Examiner Jon D. Epperson	Art Unit 1639	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Gensch et al., "Fluorescence Detection from Single Dendrimers with Multiple Chromophores" Angew. Chem. Int. Ed. 1999, 38(24), 3752-3756
	V	Yelin et al., "Large area confocal microscopy" Optics Letters, May 1, 2007, 32(9), pages 1104
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	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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